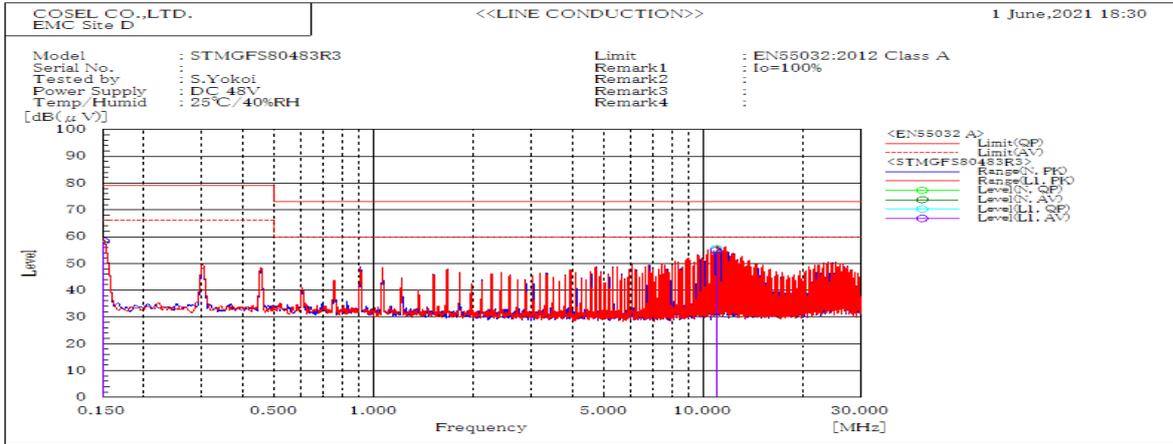
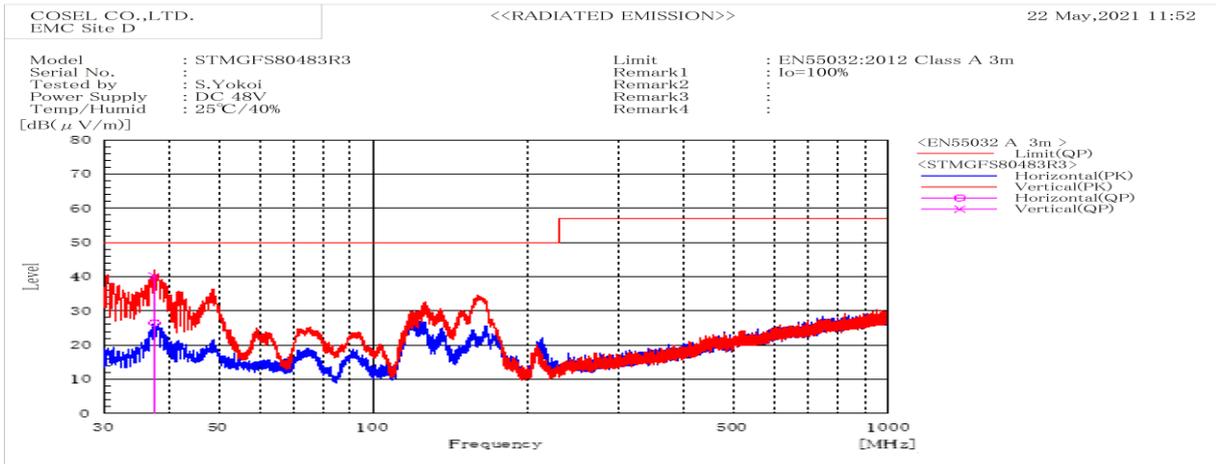


<b>DATA SHEET</b>		Date	08-Jul-21
Model	STMGFS80483R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Yokoi



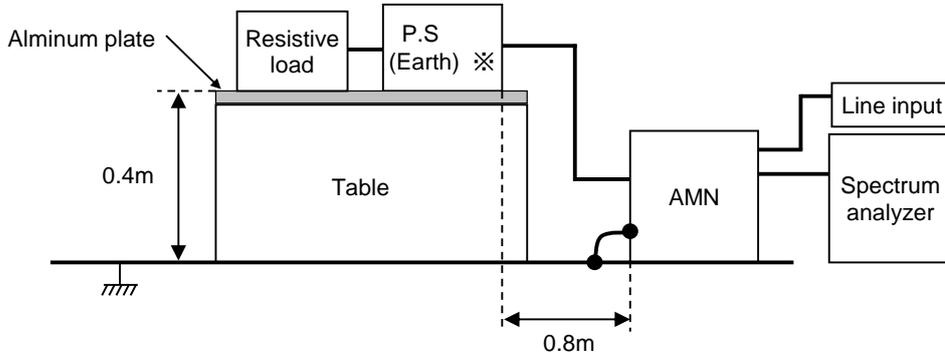
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.151	L1	58.4	58.3	79	66	20.6	7.7	Pass	
10.905	L1	55.6	54.8	73	60	17.4	5.2	Pass	
0.151	N	58.4	58.3	79	66	20.6	7.7	Pass	
10.902	N	55.5	54.9	73	60	17.5	5.1	Pass	



Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)		Margin dB		Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP	QP						
37.451	V	Stable	40.2	50	9.8	Pass	100	281.3				
37.466	H	Stable	26.5	50	23.5	Pass	199.7	39.7				

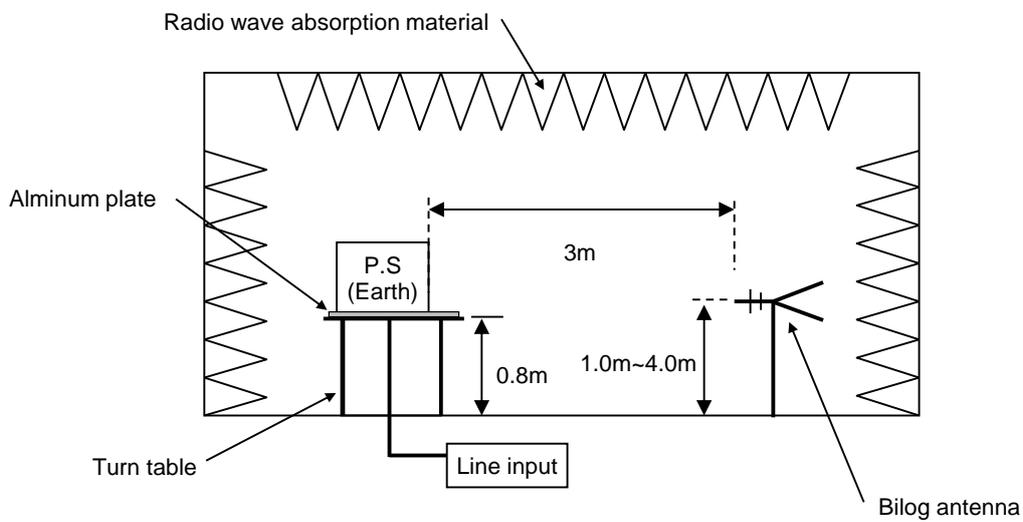
DATA SHEET		Date	08-Jul-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Yokoi

**1. Line conduction**



※External capacitor on the input side : 120μF

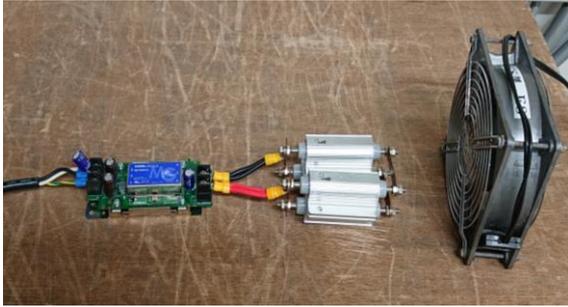
**2. Radiated emission**



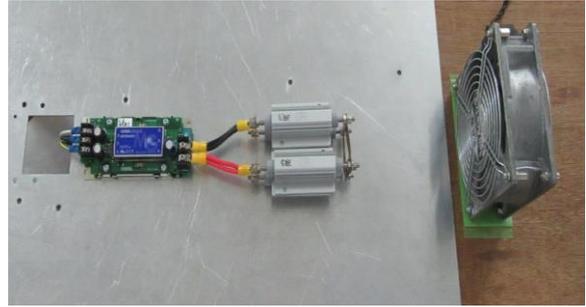
**Conditions**

Test : EMI  
 Model Name : STMGFS80□□

○Photographs of Test Set-Up  
**LINE CONDUCTION**



**RADIATED EMISSION**



○Testing circuitry

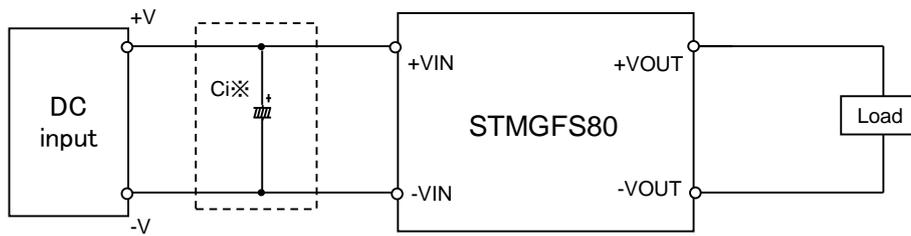


Fig.1 Testing circuitry

※Ci : External capacitor on the input side when LINE CONDUCTION

Ci : STMGFS8024□□ 220  $\mu$  F  
 STMGFS8048□□ 120  $\mu$  F